

April 2001

IGBT

SGS10N60RUF

Short Circuit Rated IGBT

General Description

Fairchild's RUF series of Insulated Gate Bipolar Transistors (IGBTs) provide low conduction and switching losses as well as short circuit ruggedness. The RUF series is designed for applications such as motor control, uninterrupted power supplies (UPS) and general inverters where short circuit ruggedness is a required feature.

Features

- Short circuit rated 10us @ $T_C = 100$ °C, $V_{GE} = 15$ V
- · High speed switching
- Low saturation voltage : $V_{CE(sat)} = 2.2 \text{ V} @ I_C = 10 \text{A}$
- High input impedance

Application

AC & DC Motor controls, general purpose inverters, robotics, servo controls





Absolute Maximum Ratings T_C = 25°C unless otherwise noted

Symbol	Description		SGS10N60RUF	Units	
V _{CES}	Collector-Emitter Voltage		600	V	
V _{GES}	Gate-Emitter Voltage		± 20	V	
1	Collector Current	@ $T_C = 25^{\circ}C$	16	Α	
I _C	Collector Current	@ T _C = 100°C	10	Α	
I _{CM (1)}	Pulsed Collector Current		30	Α	
	Short Circuit Withstand Time	@ T _C = 100°C	10	μs	
T _{SC}	Maximum Power Dissipation	$@ T_C = 25^{\circ}C$	55	W	
	Maximum Power Dissipation	@ T _C = 100°C	22	W	
T _J	Operating Junction Temperature		-55 to +150	°C	
T _{stg}	Storage Temperature Range		-55 to +150	°C	
T _L	Maximum Lead Temp. for soldering Purposes, 1/8" from case for 5 seconds		300	°C	

Notes

(1) Repetitive rating : Pulse width limited by max. junction temperature

Thermal Characteristics

Symbol	Parameter	Тур.	Max.	Units
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case		2.3	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient		62.5	°C/W

Symbol	Parameter	arameter Test Conditions		Тур.	Max.	Units
Off Cha	racteristics					
BV _{CES}	Collector-Emitter Breakdown Voltage	$V_{GE} = 0V, I_{C} = 250uA$	600			V
$\Delta B_{VCES}/$ $\Delta T_{.1}$	Temperature Coeff. of Breakdown Voltage	$V_{GE} = 0V, I_C = 1mA$		0.6		V/°C
I _{CES}	Collector Cut-off Current	$V_{CE} = V_{CES}, V_{GE} = 0V$			250	μА
I _{GES}	G-E Leakage Current	$V_{GE} = V_{GES}, V_{CE} = 0V$			± 100	nA
On Char	acteristics					
V _{GE(th)}	G-E Threshold Voltage	$I_C = 10mA$, $V_{CE} = V_{GE}$	5.0	6.0	8.5	V
	Collector to Emitter	$I_C = 10A$, $V_{GE} = 15V$		2.2	2.8	V
$V_{CE(sat)}$	Saturation Voltage	$I_C = 16A$, $V_{GE} = 15V$		2.5		V
Dynamic	c Characteristics	, <u> </u>		1	1	
C _{ies}	Input Capacitance	V 20V V 0V		660		pF
C _{oes}	Output Capacitance	$V_{CE} = 30V, V_{GE} = 0V,$ f = 1MHz		115		pF
C _{res}	Reverse Transfer Capacitance			25		pF
t _{d(on)}	Turn-On Delay Time Rise Time			15 30		ns ns
	,					
t _r t _{d(off)}	Turn-Off Delay Time	$V_{CC} = 300 \text{ V}, I_{C} = 10\text{A},$		36	50	nS
<u>'d(off)</u> t _f	Fall Time	$R_{\rm G} = 20\Omega, V_{\rm GE} = 15V,$		158	200	ns
	Turn-On Switching Loss	Inductive Load, $T_C = 25^{\circ}C$		141		μJ
E _{on} E _{off}	Turn-Off Switching Loss			215		μJ
	Total Switching Loss			356	500	μJ
E _{ts}	Turn-On Delay Time			16		ns
t _{d(on)} t _r	Rise Time			33		ns
	Turn-Off Delay Time	$V_{CC} = 300 \text{ V}, I_{C} = 10\text{A},$		42	60	ns
t _{d(off)} t _f	Fall Time	$R_{G} = 20\Omega, V_{GE} = 15V,$		242	350	ns
E _{on}	Turn-On Switching Loss	Inductive Load, T _C = 125°C		161		μJ
E _{off}	Turn-Off Switching Loss			452		μJ
Ε _{ts}	Total Switching Loss	+		613	860	μJ
T _{sc}	Short Circuit Withstand Time	V _{CC} = 300 V, V _{GE} = 15V @ T _C = 100°C	10			μs
Qg	Total Gate Charge			30	45	nC
Q _{ge}	Gate-Emitter Charge	$V_{CE} = 300 \text{ V}, I_{C} = 10\text{A},$		5	10	nC
Q _{gc}	Gate-Collector Charge	V _{GE} = 15V		8	16	nC
yc				7.5		nH

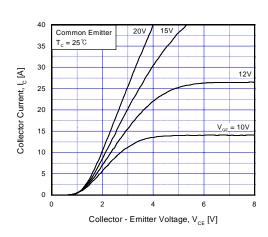


Fig 1. Typical Output Chacracteristics

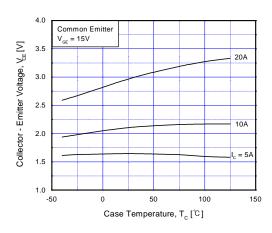


Fig 3. Saturation Voltage vs. Case
Temperature at Variant Current Level

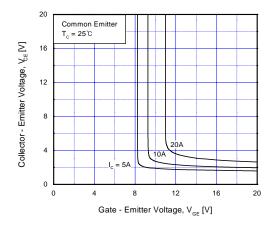


Fig 5. Saturation Voltage vs. V_{GE}

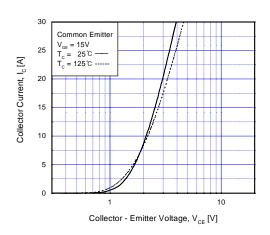


Fig 2. Typical Saturation Voltage Characteristics

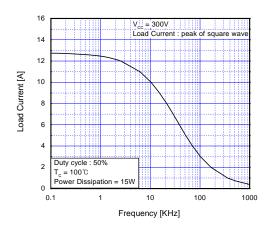


Fig 4. Load Current vs. Frequency

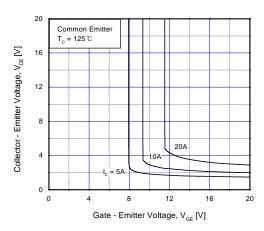


Fig 6. Saturation Voltage vs. V_{GE}

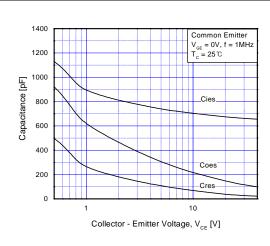


Fig 7. Capacitance Characteristics

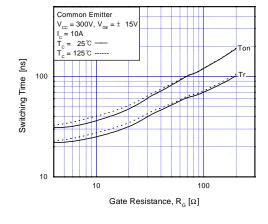


Fig 8. Turn-On Characteristics vs.
Gate Resistance

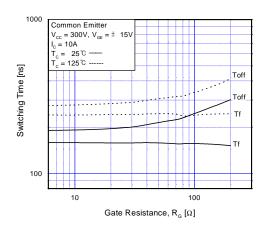


Fig 9. Turn-Off Characteristics vs.
Gate Resistance

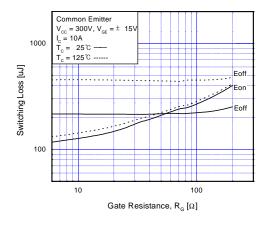


Fig 10. Switching Loss vs. Gate Resistance

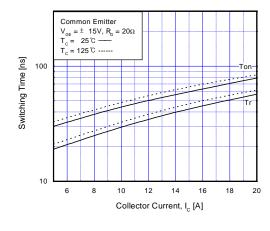


Fig 11. Turn-On Characteristics vs. Collector Current

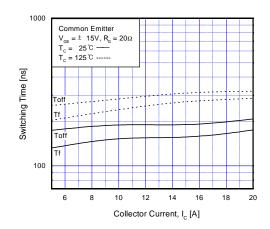
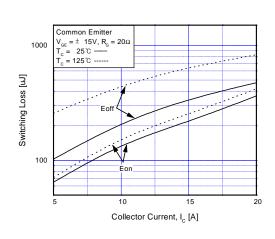


Fig 12. Turn-Off Characteristics vs. Collector Current



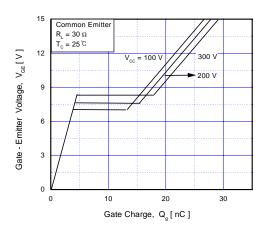
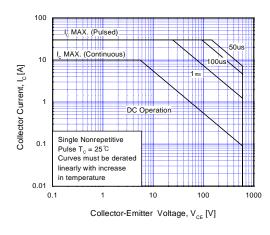


Fig 13. Switching Loss vs. Collector Current

Fig 14. Gate Charge Characteristics



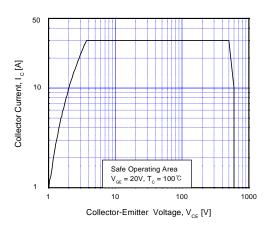


Fig 15. SOA Characteristics

Fig 16. Turn-Off SOA Characteristics

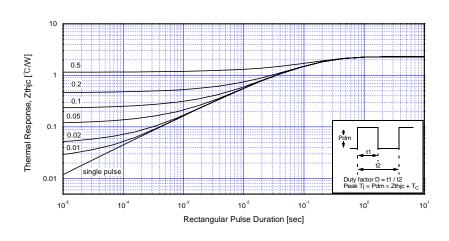
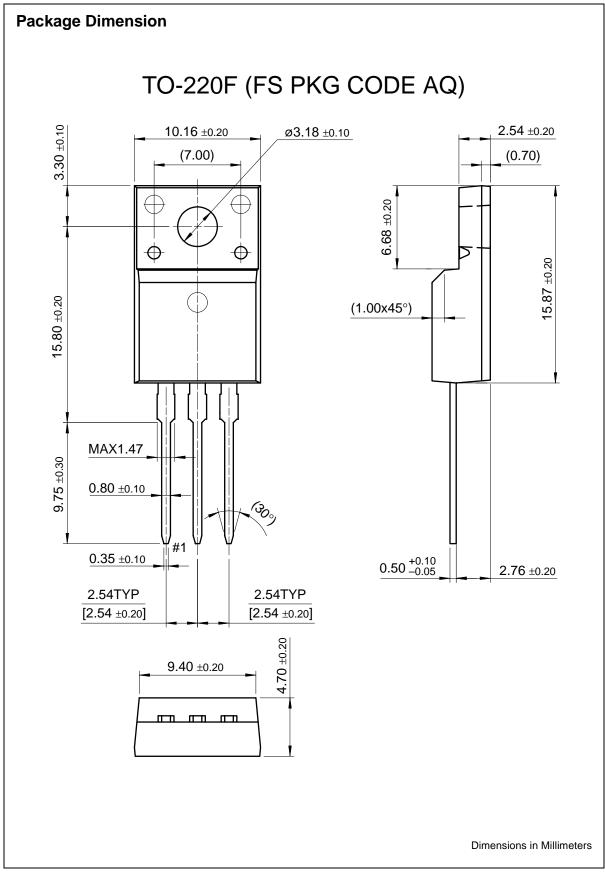


Fig 17. Transient Thermal Impedance of IGBT



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Product status/pricing/packaging

Product	Product status	Pricing*	Package type	Leads	Packing method
SGS10N60RUFTU	Full Production	\$1.61	<u>TO-220F</u>	3	RAIL

^{* 1,000} piece Budgetary Pricing

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